

# Dark current measurements

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# Main participants

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↪ **PS Operators**

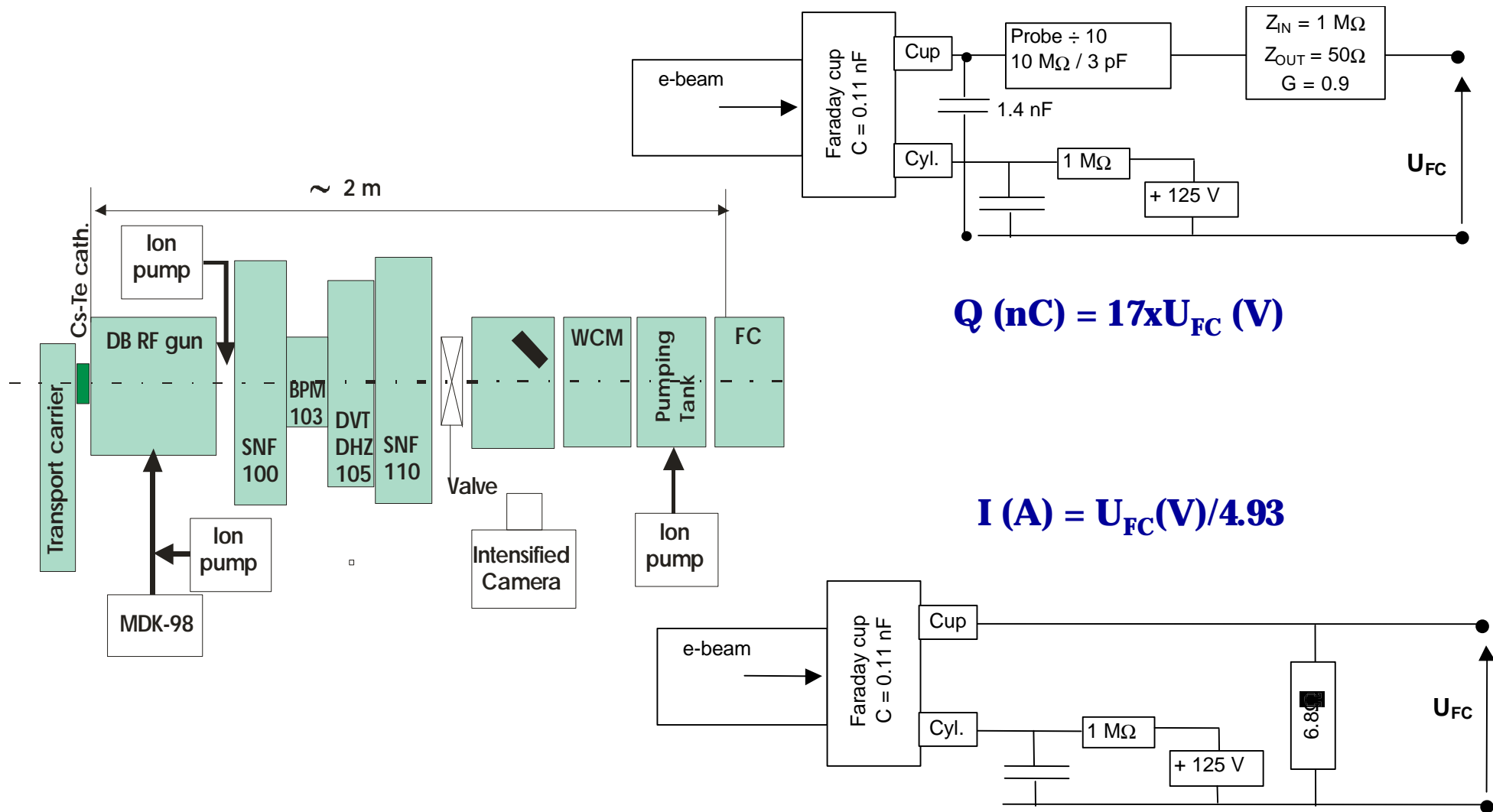
↪ **Klystron Team**

↪ **Eric Chevally**

↪ **Thibaut Lefèvre**

↪ **Guy Suberlucq**

# Measurement set-up



# Field enhancement factor and field emission area

↪ For RF gun the field emission current could be approximated by : (1)

$$\bar{I}_{FE} = \frac{5.7 \times 10^{-12} \times 10^{4.52 \times f^{-0.5}} Ae (bE)^{2.5}}{f^{1.75}} \times e^{-\frac{kf^{1.5}}{bE}}$$

↪ The modified Fowler-Nordheim plot :  $\log\left(\frac{\bar{I}_{FE}}{E^{2.5}}\right)$  vs  $\frac{1}{E}$  give :

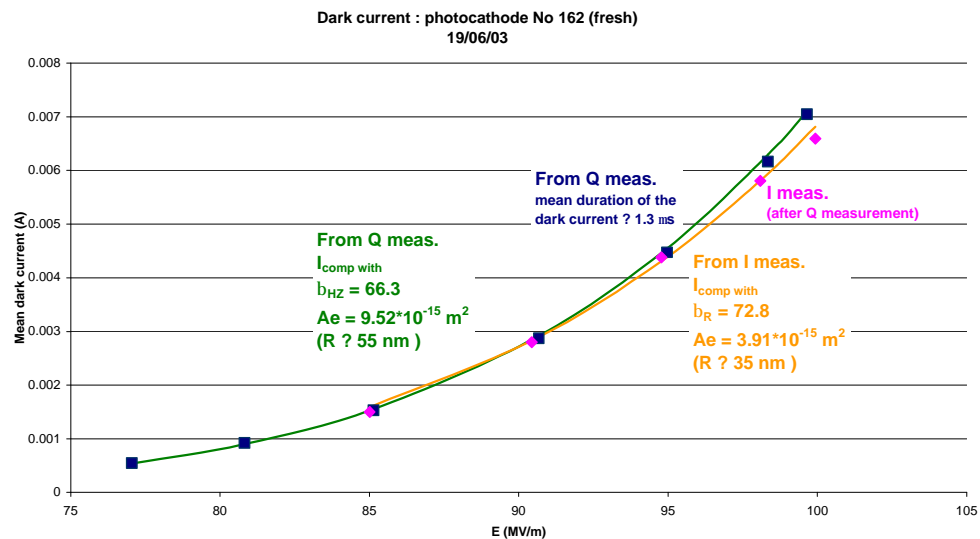
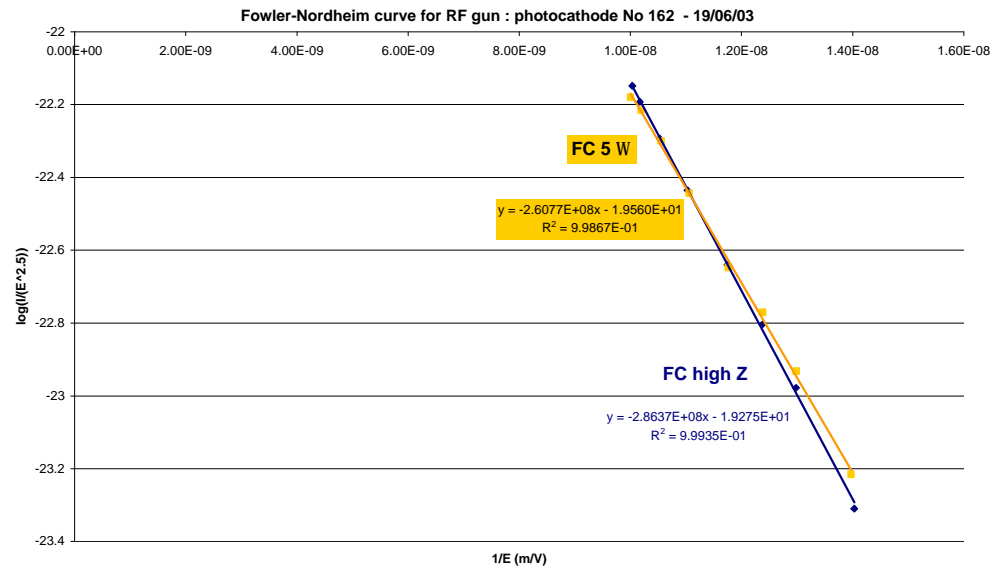
$$b = \frac{2.84 \times 10^9 f^{1.5}}{\text{slope of the plot}} \quad \text{the field enhancement factor}$$

$$\log(Ae) = \log\left(\frac{\bar{I}_{FE}}{E^{2.5}}\right)_{E \rightarrow \infty} - \log(5.7 \times 10^{-12} \times 10^{4.52 f^{-0.5}} b^{2.5}) + \log(f^{1.75})$$

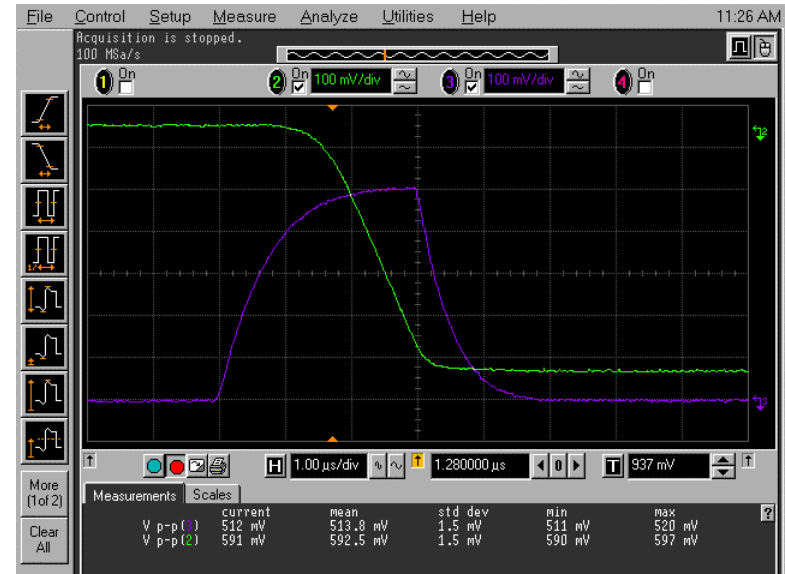
**Ae = area of a single dominant emitter or  
area of a collection of emitters of similar strengths**

(1) J.W. Wang, PhD Thesis, Stanford University (1989)

# Dark current measurement on Cs<sub>2</sub>Te photocathode



G. Suberlucq AB-ATB



CLIC Meeting 8/07/03

# Main results from dark current measurements (1)

↪ **Standard conditioning process:**

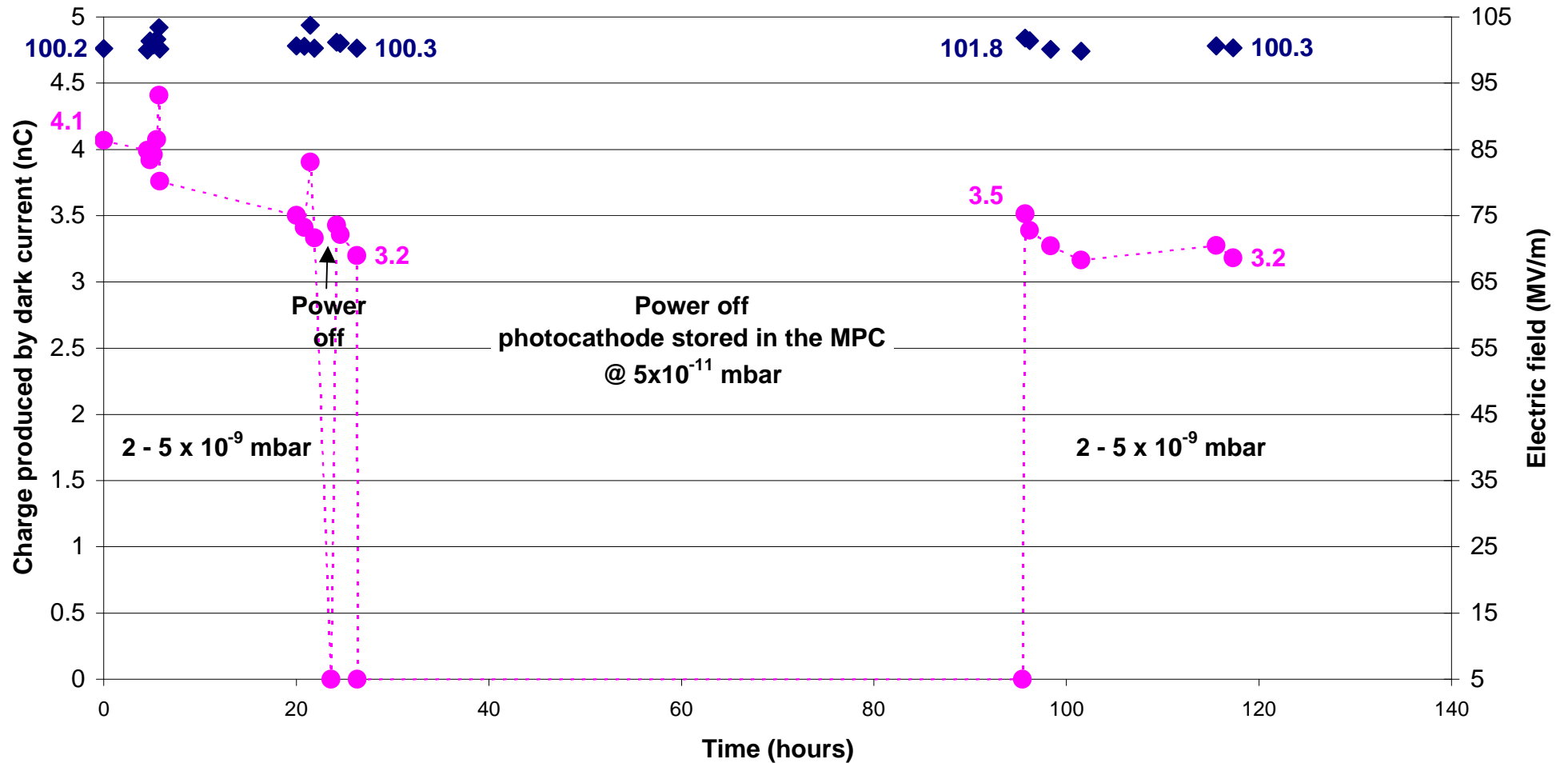
**Slow increase of the klystron output power by minimizing break-downs, until 18MW nominal power, corresponding to 100 MV / m. After more than 10 minutes without breakdown, the cathode is considered as conditioned.**

	<b>Fresh Cs<sub>2</sub>Te photo-cath.</b>	<b>Used Cs<sub>2</sub>Te photo-cath</b>	<b>Chemically cleaned copper plug</b>	<b>ICE cleaned copper plug</b>	<b>ICE cleaned used Cs<sub>2</sub>Te photo-cath.</b>
<b>f (eV)</b>	<b>3.55</b>	<b>3.55</b>	<b>4.6</b>	<b>4.6</b>	<b>4.6</b>
<b>b From - to</b>	<b>73 - 66</b>	<b>77 - 53</b>	<b>104 - 70</b>	<b>94 - 49</b>	<b>102 - 100</b>
<b>Eq.Radius (nm)</b>	<b>35 - 55</b>	<b>27 - 165</b>	<b>38 - 269</b>	<b>55 - 2616</b>	<b>31 - 37</b>
<b>I<sub>mean</sub> (mA) at 100MV/m</b>	<b>7.3 - 6.9</b>	<b>6.9 - 6.5</b>	<b>5.2 - 4.8</b>	<b>4.3 - 3.8</b>	<b>3.2</b>

**ICE : Argon ion bombardment at  $5 \times 10^{-2}$  mbar eq. N<sub>2</sub>**

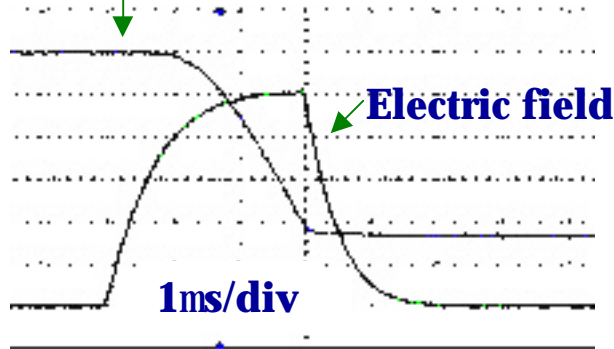
# Main results from dark current measurements (2)

Conditioning process of the Cs<sub>2</sub>Te photocathode No 162 from 100 MV/m to 105 MV/m

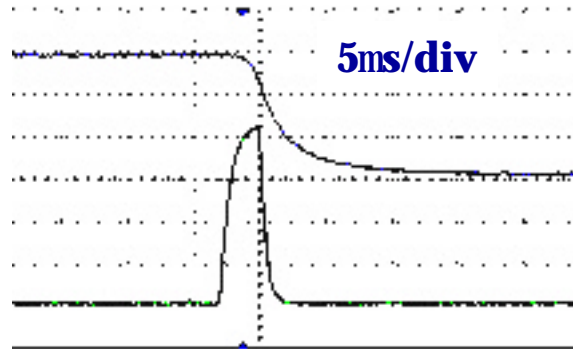


# Strange phenomena

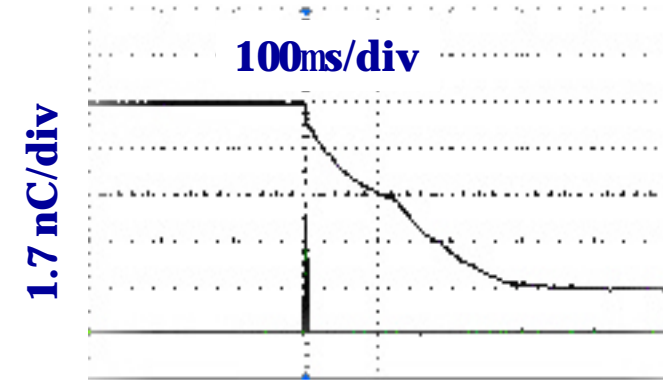
charge produced by dark current



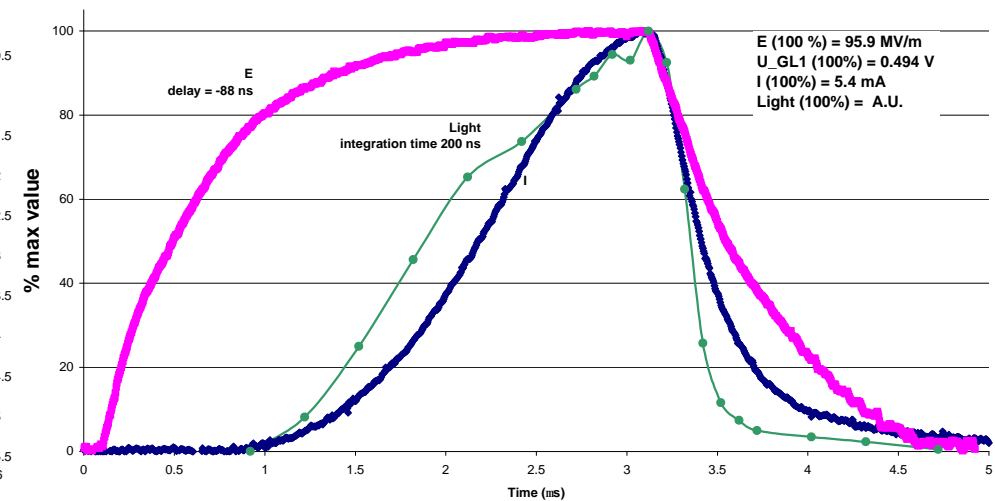
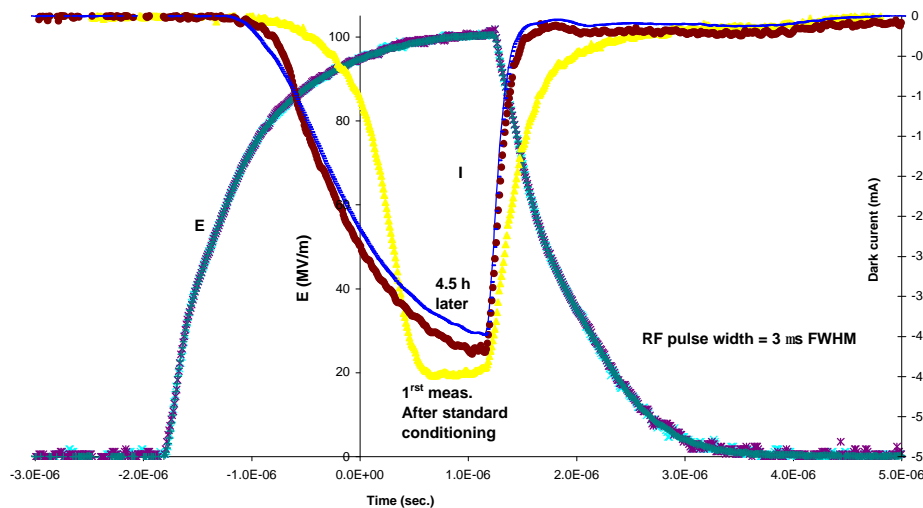
Nominal shape



Long tail shape sometime during conditioning process  
often just before an RF breakdown. Confirmed by light measurements



Evolution of the dark current shape during the conditioning process : Copper plug 4A-17 after ICE





# Conclusion

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- ✚ No major difference between Cs<sub>2</sub>Te photo-cathodes and copper plugs in term of dark current up to 100 MV/m
- ✚ Cleaning by argon ion bombardment (ICE) helps to reduce dark current
- ✚ Conditioning process of the copper plug, with or without ICE, before Cs<sub>2</sub>Te cathode preparation, helps for the photo-cathode conditioning.
- ✚ The long tail of the charge produced by dark current during the conditioning process should come from ions which can potentially destroy the photo-cathode.  
More investigations should be done.